

Cambridge University Press

978-0-931-83718-0 - Semiconductor-on-Insulator and Thin Film Transistor Technology

Edited by A. Chiang, M. W. Geis and L. Pfeiffer

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MATERIALS RESEARCH SOCIETY SYMPOSIA PROCEEDINGS VOLUME 53

Semiconductor-on-Insulator and Thin Film Transistor Technology

Symposium held December 3-6, 1985, Boston, Massachusetts, U.S.A.

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Pittsburgh, Pennsylvania

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CAMBRIDGE UNIVERSITY PRESS

Cambridge, New York, Melbourne, Madrid, Cape Town,
Singapore, São Paulo, Delhi, Mexico City

Cambridge University Press

The Edinburgh Building, Cambridge CB2 8RU, UK

Published in the United States of America by Cambridge University Press, New York

www.cambridge.org

Information on this title: www.cambridge.org/9780931837180

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First published 1986

First paperback edition 2012

A catalogue record for this publication is available from the British Library

ISBN 978-0-931-83718-0 Hardback

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